

Notice of References Cited	Application/Control No. 10/756,381		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner Djenane M. Bayard		Art Unit 2141	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2002/0018643	02-2002	Okada et al.	386/95
*	C	US-2001/0046371	11-2001	Ando et al.	386/70
*	D	US-2002/0131761	09-2002	Kawasaki et al.	386/65
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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